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You may want to try an Advanced Search for additional options.

Please review the Quick Tips below or for more information see the Search Tips.

Quick Tips

• Enter your search terms in <u>lower case</u> with a space between the terms.

sales offices

You can also enter a full question or concept in plain language.

Where are the sales offices?

 Capitalize <u>proper nouns</u> to search for specific people, places, or products.

John Colter, Netscape Navigator

Enclose a phrase in double quotes to search for that exact phrase.

"museum of natural history" "museum of modern art"

• Narrow your searches by using a + if a search term <u>must appear</u> on a page.

museum +art

• Exclude pages by using a - if a search term <u>must not appear</u> on a page.

museum -Paris

Combine these techniques to create a specific search query. The better your description of the information you want, the more relevant your results will be.

museum +"natural history" dinosaur -Chicago

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A maximum of 100 results are displayed, 25 to a page, sorted by Relevance in Descending order.

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IEEE Journal or Magazine

IET JNL

IET CNF

IEEE Conference

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IEEE CNF

Proceeding

IET Conference

Proceeding

IEEE STD IEEE Standard

1. Linearization of large-signal scattering functions

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Microwave Theory and Techniques, IEEE Transactions on Volume 53, Issue 4, Part 1, April 2005 Page(s):1369 - 1376

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AbstractPlus | References | Full Text: PDF(448 KB) | IEEE JNL

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